Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/685,599	SHIROTA ET AL.	
Examiner	Art Unit	
Thien F. Tran	2811	

SEARCHED				
Class	Subclass	Date	Examiner	
257	315-317	7/10/2005	π	
257	319-321	7/10/2005	тт	
		-	<u> </u>	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
257	316-317	7/10/2005	тт		
257	319-321	7/10/2005	π·		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
	,			
	ā .			
·				